



AT-LA500

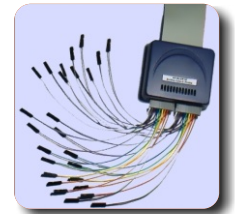
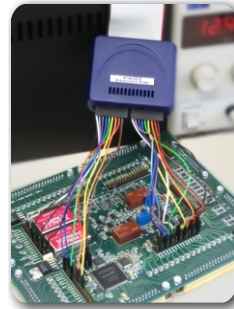
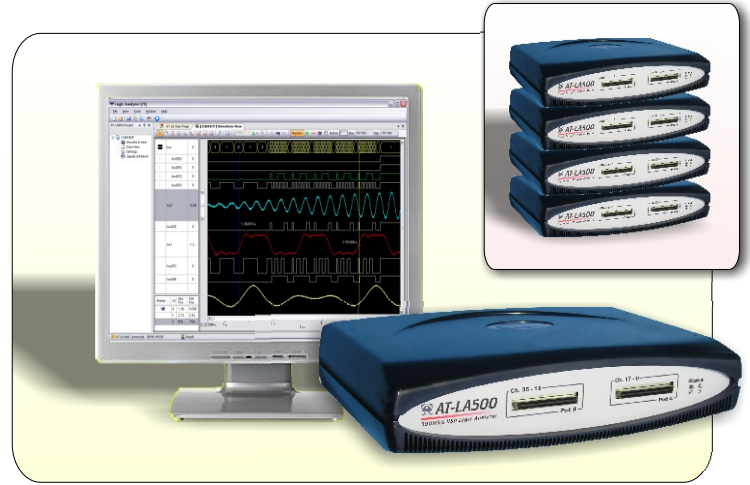
500 MS/s USB Logic Analyzer 1.5GS/s with *GigaView* acquisition

The Easiest and Cost-Effective Tool to Solve Your Toughest Digital Debugging Problems

The AT-LA500 USB PC Based Logic Analyzer is the ideal solution to find and solve any digital testing issue.

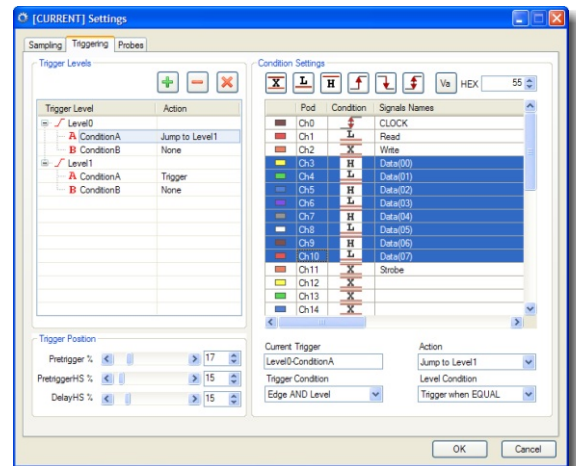
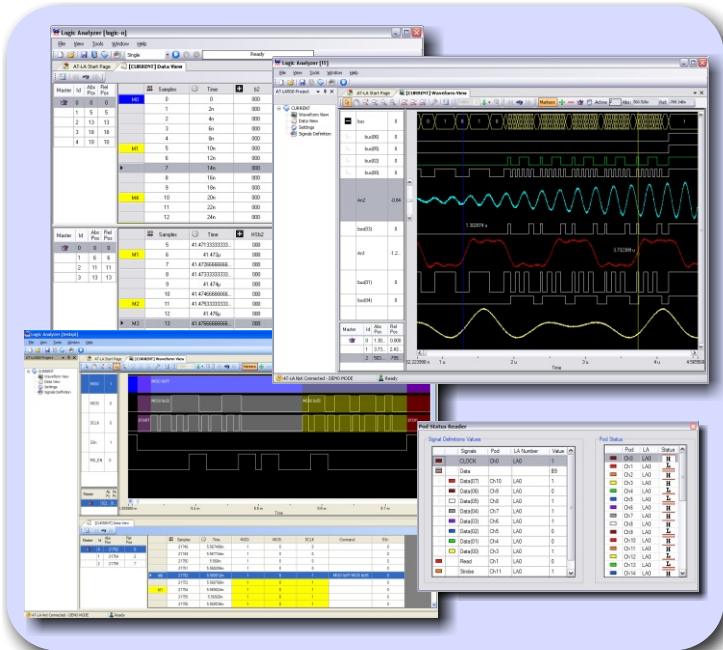
The AT-LA500 USB provides excellent performance and easy-to-use interface, combining the advantages of a compact size instrument with the flexibility of your PC for data management and visualization, all at affordable price. AT-LA500 can be also tightly integrated with most popular oscilloscopes to provide a complete high performance and low cost mixed signal test solution.

- 36 Channels @ 500MS/s
- *GigaView*: 36 Channels @ 1.5GS/s
- Up to 8 instruments linkable with AT-XSS bus
- 500 MHz Timing Analysis
- 200 MHz DDR / 100 MHz SDR State Analysis
- 31 trigger levels
- Serial Protocol Analysis with advanced trigger options
- Mixed signal Analysis (by oscilloscope integration)
- Up to 4 Million Samples on all channels
- Up to 130 min. of acquisition time
- 3 probe sets hot pluggable
- 4 programmable and independent thresholds on each instrument
- Digital Pattern Generator - Sampler (optional)



Powerful software allows to control advanced AT-LA500 functions using a user-friendly graphic interface:

- Easy to use instrument control and configuration
- Multiple display windows with cursors for simple measurements: Mixed Signal Waveform and Data View
- USB 2.0 interface (compatible 1.1) to transfer data to the PC within seconds
- LabView and C/C++ SDK (Software Development Kit)
- Windows 2000/XP OS



Tech Specs:

Channels:	36 (up to 288 channels with AT-XSS bus)
Linkable instruments with AT-XSS bus:	Up to 8
Maximum sampling frequency:	500MSamples/s + 1.5GSamples/s with <i>GigaView</i>
Timing Analysis:	500MHz
State Analysis:	200MHz DDR / 100MHz SDR It is possible to sample on an external clock that comes from different combination of 4 dedicated inputs
Memory Depth:	Up to 4M Samples + 1k Samples @ 1.5GS/s
Trigger Settings:	Edge Condition: No edge, Rising Edge, Falling Edge, Both Edges on all channels Level Condition: Condition verified if the selected inputs are equal (or different) to the pattern that the user sets
Trigger Levels	31
Trigger Mode:	Edge AND Level; Edge OR Level; Edge THEN Level; Level THEN Edge; Always Trigger; Never Trigger; Manual Trigger
Dimensions (WxLxH):	17.3 x 27.3 x 6.7 cm
Weight:	700g
Interface:	USB 2.0 (compatible with USB 1.1)
Power Supply:	12 VDC

<i>Probes Tech Specs:</i>	<i>Active Hi-Z Probe</i>	<i>Active Low-C Probe</i>	<i>Passive Probe</i>
Input Capacitance:	9pF	<0.1pF	//
Input Resistance:	1.1M Ω	1.1k Ω	//
Maximum Toggle Rate:	80MHz	130MHz	100MHz
Linear Input Voltage Range:	-40V to +40V	-10V to +10V	0 to 5V
Threshold Voltage:	-40V to +40V in 20mV steps	-10V to +10V In 20mV steps	2V
Number of Thresholds:	2 programmable and independent	2 programmable and independent	1 Fixed

AT-LA500 is a test equipment instrument designed and made in Italy by Active Technologies. The company was founded in 2002 by a staff of engineers expert in semiconductor test equipment and instrumentation design.

Active Technologies is a supplier of innovative and avant-garde Automated Test Equipment and electronic instrumentation to world wide semiconductor company leaders.

Info and orders: info@activetechnologies.it
sales@activetechnologies.it
Technical Support: support@activetechnologies.it
Phone: +39 0532 91456
Fax: +39 0532 970134



Active Technologies
via Bela Bartok, 29/B
44100 Ferrara - Italy